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December 14, 1999

Federal Communications Commission Equipment Approval Services 7435 Oakland Mills Road Columbia, MD 21046 Attn: Frank Coperich / Kwok Chan

SUBJECT: Samsung Electronics Co., Ltd. FCC ID: A3LSCH850 731 Confirmation Number: EA95417 Correspondence Reference No.: 11003

Dear Frank / Kwok:

Submitted herewith, on behalf of Samsung Electronics Co., Ltd., is an amendment in response to your email dated December 13, 1999 requesting additional information for the subject application.

- 1. Attached are photos of the optional holster used in the body-worn SAR test. As the photographs show, there are no metallic parts on the optional holster.
- 2. Attached is the remeasured radiated and SAR test data for SCH-850. Please note that we have retested the head and hand SAR using the SPEAG SAR system, and the body-worn SAR using the IDX SAR system.
- 3. Please note that Samsung FCC ID: A3LSCH8500 (EA95488) and FCC ID: A3LSCH8600 (EA95489) are currently being retested, and will be filed separately upon completion of the tests.
- 4. Listed below is the information we received from SPEAG on 12/3/99 stating the conversion factor for the muscle material at 835MHz, and the appropriate conductivity and permittivity parameters for the SPEAG probe S/N: 1368. Based on this information, the data derived from the SPEAG system is comparable to the data derived using the IDX system for body-worn SAR.

SN:1368 – brain 900MHz – eps=42.5, sig=0.85, ConvF=5.76 SN:1368 – muscle 900MHz – eps=55.96, sig=0.97, ConvF=5.59 (3% lower than 5.76) SN:1368 – muscle 835MHz – eps=56.2, sig=0.95, ConvF=5.7 (1% lower than 5.76)

5. We confirm that the RF exposure user manual warning statement uploaded on 12/1/99 is applicable.

We trust this information is sufficient to issue the grant asap. If you have any further questions, please do not hesitate to contact us. Thank you.

Sincerely,

Randy Ortanez President & Chief Engineer

cc: Ben Kim, Engineering Manager Samsung American QA Lab

